

Notice of References Cited	Application/Control No. 10/574,858		Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
	Examiner AMENE S. BAYOU		Art Unit 3746	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,446,853	05-1984	Adcock, Thomas P.	126/707
*	B	US-6,849,667	02-2005	Haseyama et al.	521/170
*	C	US-5,272,285	12-1993	Miller, T. Scott	181/202
*	D	US-7,107,601	09-2006	Arai, Takashi	720/651
*	E	US-5,496,156	03-1996	Harper et al.	417/312
*	F	US-7,134,847	11-2006	Nishihara et al.	417/312
*	G	US-6,152,703	11-2000	Yoshimura et al.	417/312
*	H	US-7,033,150	04-2006	Nozaki et al.	417/569
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Inform Industries European Edition 2,2009 (IIEE),Ticon			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.